

Docket No.: 60188-044



Receipt
✓ #6 #1
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Hirokazu YONEZAWA, et al.

Serial No.: 09/810,518

Filed: March 19, 2001

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Group Art Unit:

Examiner:

For: APPARATUS AND METHOD FOR CALCULATING TEMPORAL DETERIORATION
MARGIN AMOUNT OF LSI, AND LSI INSPECTION METHOD

REQUEST FOR CORRECTED FILING RECEIPT

Commissioner for Patents
Washington, DC 20231


Sir:

Attached is a copy of the Filing Receipt received from the U.S. Patent and Trademark Office in the above-referenced application. It is noted that the number of total and independent claims is incorrect on the Filing Receipt. **Please correct the number of total claims to reflect 15 and the number of independent claims to reflect 4.**

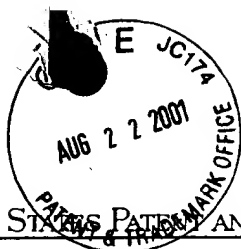
It is requested that a corrected Filing Receipt be issued.

Respectfully submitted,

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UNITED STATES PATENT AND TRADEMARK OFFICE

COMMISSIONER FOR PATENTS
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WASHINGTON, D.C. 20231
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APPLICATION NUMBER	FILING DATE	GRP ART UNIT	FIL FEE REC'D	ATTY. DOCKET NO	DRAWINGS	TOT CLAIMS	IND CLAIMS
09/810,518	03/19/2001		0.00	60188-044	11	15	4

CONFIRMATION NO. 6189

20277
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FILING RECEIPT

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OC000000006218837*

JUN 27 2001

MCDERMOTT, WILL & EMERY

Date Mailed: 06/25/2001

Receipt is acknowledged of this nonprovisional Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. **If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Customer Service Center. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the USPTO processes the reply to the Notice, the USPTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).**

Applicant(s)

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Domestic Priority data as claimed by applicant

Foreign Applications

JAPAN 2000-076087 03/17/2000

If Required, Foreign Filing License Granted 06/22/2001

Projected Publication Date: To Be Determined - pending completion of Missing Parts

Non-Publication Request: No

Early Publication Request: No

Title

Apparatus and method for calculating temporal deterioration margin amount of LSI, and LSI inspection method